

CDF Operations Report

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All Experimenters' Meeting



Stores summary

Date	Store	Duration (h)	Inst Lum (initial)	Int Lum (delivered)	Int Lum (live)	3
Mo 3/24	2343	10.3	32.5e30	804.8	598.8	74.4%
We 3/26	2357	20.9	28.9e30	1180.6	989.5	83.8%
Th 3/27	2361	13.0	18.1e30	538.9	503.8	93.5%
Sa 3/29	2370	19.6	30.1e30	1212.0	702.8	58.0%
Su 3/30	2372	0.75	0.5e30	1.1	0.7	68.2%
Total		64.6		3.7 pb ⁻¹	2.8 pb ⁻¹	75%

2.2 pb⁻¹ physics data with silicon

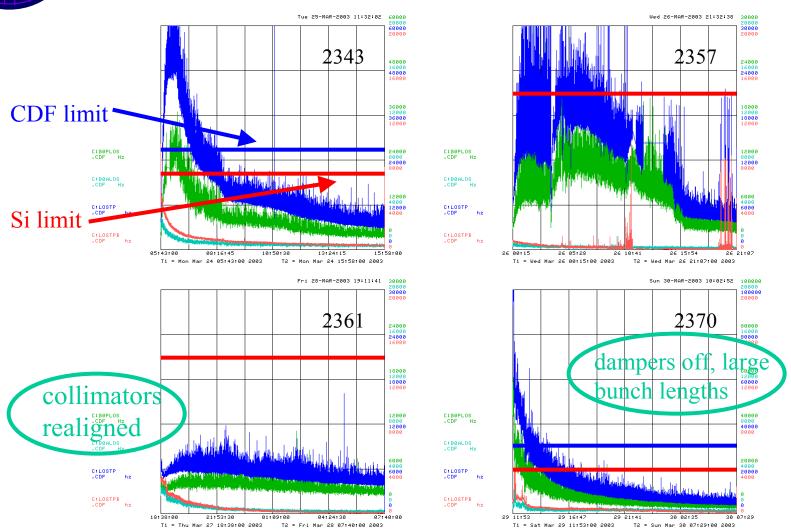


Overview of stores

- Store 2343
 - Once losses were under control, ran smoothly
 - Several HV trips due to loss spikes
- Store 2357
 - Lots of HV trips due to loss spikes
 - Silicon in and out all store
 - High losses, ACNET monitoring unreliable, in-store studies
- Store 2361
 - Low losses, smooth running
 - A few test runs to study TOF triggers
- Store 2370
 - Recovering from power cut --- more later



Losses at CDF



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Power cut at B0

- UPS shut off by mistake Friday morning
 - Lost power to the entire controls systems for B0's experimental infrastructure
 - Systems "failed safe" and fired every alarm we have; all experiment power cut
- Recovery
 - Controls system analog input hardware was difficult to revive
 - Back to life by afternoon, begin detector check-out
- Casualties
 - Solenoid LHe supply evaporated away, took a day to replenish
 - Blown ammeter in silicon PS, fixed on access
 - One HV problem in forward muon detector
 - Appeared after several hours of stable operation, will address on next access
 - Muon TDC problems
 - Not caught until store 2370, lost several hours diagnosing
 - Fixed



Conclusions

- When losses are low, CDF runs very efficiently (cf. Thursday's store and today's store)
 - Few HV trips
 - Quick integration of silicon
- Nothing irretrievably lost from Friday power cut
 - Will investigate/fix muon HV problem on next access
- Battery of trigger tests foreseen for this week to improve physics efficiency at higher L1 accept rates